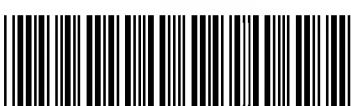


<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10560860	YOSHINO, EIKO
	<b>Examiner</b>	<b>Art Unit</b>
	Vanchy Jr., Michael	2624

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
382	187	11/8/2007	Vanchy Jr., Michael
345	179	11/8/2007	Vanchy Jr., Michael

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Used east to text search.	11/8/2007	Vanchy Jr., Michael
Used previous search history.	12/4/2008	Vanchy Jr., Michael

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

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